# Partial Discharge Properties of PET Film with Carbon Black

Young-Hwan Lee\*, Jong-Chan Lee\*\*, Yong-Sung Choi\*\*\* and Dae-Hee Park\*\*\*

Abstract - This paper presents an investigation of the phase-resolved partial discharge (PD) pattern of PET (Poly Ethylene Telephthalate) films with carbon black particles. The phase-resolved PD pattern and statistical parameter from PET samples according to the number of included semiconductor particles were measured. The measurement system consisted of a conventional PD detector using a digital signal processing technique. The partial discharge patterns of the PET films that include the semiconductor particles were investigated to simulate an actual situation that may exist in the cable. In addition, difference of PD patterns between semiconducting particles in PET films and artificial voids was studied. The relationship between the numbers of semiconductor particles in PET films was discussed through the difference of  $\psi$ - q-n distribution and statistical analysis.

**Keywords**: Partial discharge, PET film, Carbon black

### 1. Introduction

Polymers used in electric power cable applications must have superior electrical and mechanical properties. Part cularly, the macromolecule of polyethylene type is widely used in power cables [1]. Most high-voltage power cables also use a semiconducting layer between the concuctor and the layer of insulation. Due to the semiconducting layer, semiconducting particles can be crea ed over time.

A nong the various degradation mechanisms that affect the reliability of HV apparatus, those regarding insulation systems are often PD phenomena; that is, partial breakdown of gas or liquid inclusions in the solid insu ation. PD phenomena accelerate the local degradation and can generate electrical trees that are the final stage lead ng to breakdown. Since PDs are essentially electron avalanches, they give rise to an impulse of electric charge, which produces a burst of current and voltage signals outs de of the insulation system. The separation and iden ification of PD features is, thus, a fundamental requirement to obtain effective insulation diagnosis and avoid misleading evaluation of the defects generating the

In this paper, partial discharge patterns of the PET films, which include semiconductor particles, were investigated to simulate the actual situation that may exist in power

## 2. Experimental

The samples used in this experiment were PET films, including semiconducting particles with a size of 1 mm<sup>2</sup> between two 100 µm thick PET films as shown in Fig. 1. Insulation oil was filled to the rim of the upper electrode to minimize surface discharge. The inception voltage applied to the samples was 0.7kV.

Partial discharge was measured by the analogue PD Hipotronix detector CDO-77A (Fig. 2). The measured signal was digitalized through a digital oscilloscope (HP 54522A, 2Gsa/s) and data was transferred to a PC through GPIB interface.

The data acquired were processed repeatedly during a particular cycle, and were saved by the maximum discharge amount (Hqmax (\psi)), average discharge amount (Hqn  $(\psi)$ ), number of discharge (Hn  $(\psi)$ ), etc. It is important to keep external noise to a minimum level because the partial discharge signal is measured in a PC. To accomplish this, the filtered signal in the PD detector was basically software filtered through FIR (Finite Impulse Response) and any voltage smaller than partial discharge was removed before signal processing.

Receir ed: June 5, 2003; Accepted: January 19, 2004

cables. Additionally, disparity of PD patterns between semiconducting particles in PET films [3] and artificial voids were studied. Partial discharge measured by the phase-resolved partial discharge [4, 5] was analyzed using statistical operator [6, 7] to evaluate the change in partial discharge pattern. These results may provide essential information about various partial discharge sources.

School of Electrical and Electronic and Information Engineering, Wonkwang University, Korea (lyh201@wonkwang.ac.kr).

Erik Jonsson School of Engineering and Computer Science. UTD, JSA (cosmos@utdallas.edu).

School of Electrical and Electronic and Information Engineering, Wonkwang University, Korea (biochips@wonkwang.ac.kr).

School of Electrical and Electronic and Information Engineering, Wonkwang University, Korea (parkdh@wonkwang.ac.kr).

PD patterns of the samples, which include semiconducting particles (1~5), were analyzed by adding the number of semiconducting particles and the discharge time. The discharge amount measured in each sample were shown and analyzed by the  $\psi$ -q-n distribution. Furthermore, the PD pattern of the PET film with 15mm  $\psi$  void was tested to gain an understanding of the difference of PD patterns shown in the artificial void.

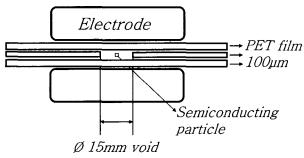


Fig. 1 Electrode and sample structure

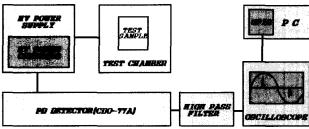


Fig. 2 PD detection system

#### 3. Results and Discussion

## 3.1 PD patterns in 15mm ψ void to approve 1~3kV

Fig. 3 shows  $\psi$ -q and  $\psi$ -n distribution results of 100/m thick PET film for different applied voltages that are gradually increased from 1 to 3kV, which are higher than the starting voltage of partial discharge. With the increment of the applied voltage, the amplitude of discharge pulse and the number of discharge pulses were increased, while the distribution of pulses was relaxed. Also, we discovered that the pulse number generated in the negative half-period is greater than the pulse number generated in the positive half-period.

The pulse amplitudes of the partial discharge were abnormal at relatively low applied voltage, but were relaxed and became normal with increments of applied voltage. It is suspected that the discharge in relatively low voltage occurs at the partial area of void interior and the number of discharge channels at the full area of the void becomes greater as the applied voltage is increased.

Moreover, the effect of space charge by partial discharge pulse that took place previously cannot be neglected.

The properties by phase change are as follows. The amplitude of discharge pulse near the starting voltage of 1kV partial discharge showed a decreasing pattern with the central 45° after beginning positive and negative periods. But, the amplitude of discharge pulse was increased in both directions with center of 45° degree 1.5kV, and had pattern to have phase difference more than 2.2kV. The number of discharge pulses showed a similar pattern to the amplitude of discharge pulse around the starting voltage of 1kV partial discharge and also showed the phase difference similarly with the amplitude of discharge pulse more than 2.2kV.

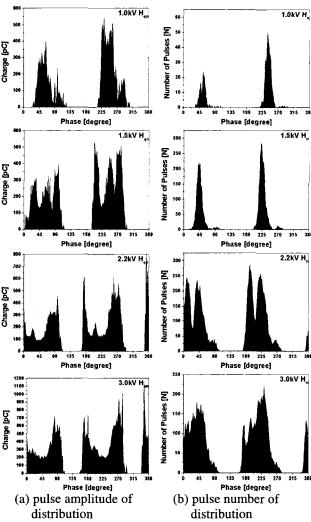


Fig. 3  $\psi$ -q and  $\psi$ -n distribution according to the applied voltage

# 3.2 PD patterns with one piece of added semiconducting particle

With the addition of the semiconducting particle, PD occurs in the surrounding microscopic void of semiconducting particles. Therefore, the number of conductive paths multiplies as the number of added semiconducting particle increases. PD patterns with one

piece of added semiconducting particle as discharge progresses are shown in Fig. 4. The discharge amount appeared in a particular period because the discharge was developed after a typical PD pattern, such as the streamer-process pattern. After all, discharge amount q and discharge number n are found to be decreased over time. PD was increased or decreased within a particular period, or PD hardly occurred at all. As compared with PD patterns in the artificial void, the distribution differences were shown because the time difference of applied voltage an the patterns itself were similar.

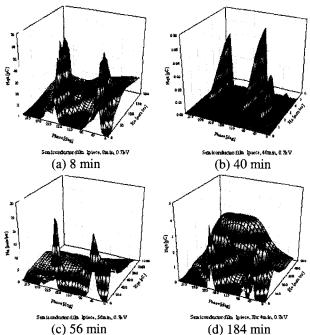


Fig. 4 PD patterns to add one piece of semi-conducting particle at an applied voltage of 0.7 kV

# 3.3 PD patterns with three pieces of added semiconducting particles

PI) patterns with three pieces of added semiconducting particles are shown in Fig. 5. The period of PD patterns was prolonged with increments of the particle number and PD vas picked up a long time later. It is suspected that void size was finally increased and that microscopic void was increased together around the semiconducting particle as the particle number increases, as described above. Entire PD I atterns were not clearly different and were a bit spread out compared with the phase when one piece of particle was idded. Also, the phase movement of mainly generated PD was investigated over time.

# 3.4 PD patterns with five pieces of added semiconducting particles

PI) patterns with five pieces of added semiconducting

particles were shown in Fig. 6. It was shown nearly in a pattern that was more typical than before. This is due to the increment of the conductive path number according to the increment of particle number. The changed period of patterns became longer than in the case of three pieces of added particles, but the entire discharge amount decreased a bit earlier. However, it shows a particular discharge amount and discharge number for a longer time.

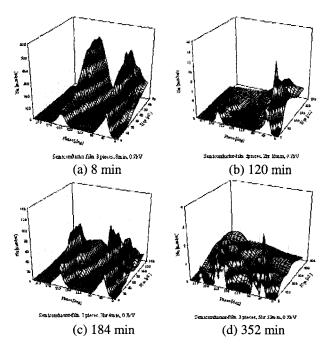


Fig. 5 PD patterns to add three pieces of semiconducting particles at an applied voltage of 0.7kV

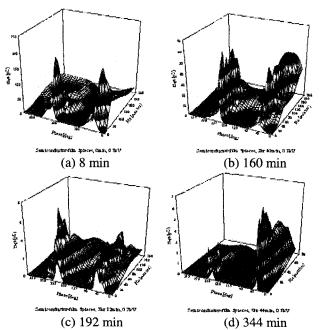


Fig. 6 PD patterns to add five pieces of semiconducting particles at an applied voltage of 0.7kV

#### 4. Conclusion

In this paper, the difference of PD patterns between semiconducting particles in PET films and artificial voids was discovered. The partial discharge pulse was measured with increments of the number of semiconducting particles and changes of discharge and PD pattern through distribution were analyzed. The semiconducting particles were influenced on partial discharge in insulators, but were not observed as the distinguishing singular phenomenon with artificial void. With addition of the semiconducting particle, PD occurred in the surrounding microscopic void of semiconducting particles. Therefore, the number of conductive paths increases as the number of semiconducting particle increases. This can be thought that void size was finally increased and the microscopic void was increased together around semiconducting particles according to increments of particle number as referred before.

## Acknowledgement

This work has been supported by EESRI (R-2003-B-274), which is funded by MOCIE (Ministry of Commerce, Industry and Energy).

#### References

- [1] Benny Thomas, "Partial Discharge Degradation and Breakdown Studies in Polypropylene Films", 1996 IEEE International Symposium on Electrical Insulation, pp.521-524 (1996)
- [2] A. Cavallini et al., "A New Approach to the Diagnosis of Solid Insulation Systems Based on PD Signal Interface", IEEE Electrical Insulation Magazine, Vol. 19, No. 2, pp. 23-30 (2003)
- [3] Tamon Ozaki, "A Partial Discharge Behavior of Piled PET Films", 1995 IEEE International Symposium on Electrical Insulating Material, Tokyo, Japan, pp. 459-462 (1995)
- [4] Kaori Nakao, Takeshi Kondo, Yasuo Suzuoki, Teruyoshi Mizutani, "ψ-q-n Patterns and Current Shapes of Partial Discharge in Void", 1998 Asian International Conference on Dielectric Electrical Insulation and the 30th Symposium on Electrical Insulating Materials, Toyohashi, Japan (1998)
- [5] B.A. Fruth, D.W. Gross, "Partial Discharge Signal Conditioning Techniques for On-Line Noise Rejection and Improvement of Calibration", 1996 IEEE International Symposium on Electrical Insulation, pp. 397-400 (1996)
- [6] Lutz Niemeyer, "A Generalized Approach to Partial Discharge Modeling", IEEE Transaction on Dielectrics and Electrical Insulation, Vol. 2, No. 4, pp. 510-528 (1995)

[7] F. H. Kreuger, "Partial Discharge Detection in High Voltage Equipment", Butteworths, London (1989)



## Young-Hwan Lee

He received his B.S degree in Electrical Engineering from Hanyang University in 1982. He is currently taking a Master's course in the Department of Electrical Materials Engineering, Wonkwang University. His main research interests are in the areas of high voltage, gas

discharge and electrodeless lamps for lighting.



#### Jong-Chan Lee

He received his B.S., M.S. and Ph.D. degrees in Electrical Materials Eng. from Wonkwang Univ. in 1997, 1999 and 2003, respectively. Since 2003, he has been working at UTD in the USA as a Postdoctoral Fellow. His main research interests are in the areas of flat

panel display, high voltage, electrodeless discharge, and MEMS and its applications.



# Yong-Sung Choi

He received his B.S., M.S. and his Ph.D. degrees in Electrical Eng. from Dong-A Univ. in 1991, 1993 and 1998, respectively. He worked as a Postdoctoral Fellow at the Japan Advanced Institute of Science and Technology from 1999 to 2000. He then went on to work with T.

Kawai of Osaka University as a JSPS Fellow from 2001 to 2002. He has also been employed as a Research Professor at Wonkwang University. His main research interests are in the areas of biotechnology (biochip), high voltage, and discharge and its applications.



#### Dae-Hee Park

He received his B.S. and M.S. degrees in Electrical Eng. from Hanyang Univ. and his Ph.D. degree from Osaka University in 1979, 1983 and 1989, respectively. He worked at the LG Cable Research Institute as a Senior Researcher from 1974 to 1992. After

that, he joined the School of Electrical, Electronics and Information Eng., at Wonkwang University where he is currently a Professor. He was a Visiting Professor at MSU in the USA from 1999 to 2000. His main research interests are in the areas of insulating and dielectric materials, new lighting sources and discharge.